

**Search Notes**

Application/Control No.

10/780,844

Examiner

James D. Ewart

Applicant(s)/Patent under  
R examination

BACKES ET AL.

Art Unit

2617

**SEARCHED**

Class	Subclass	Date	Examiner
455	63.1	5/31/2006	JDE
	63.3		
	434		
	447		
	450-454		
	455		
	463		
	464		
	509		
	515		
	516		
370	329		
	330		
	332		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
obtained class 455 search from Bill Trost	2/7/2006	JDE
Spoke to Steve D'Agosta for search suggestions	2/7/2006	JDE
Obtained search from Vo Nguyen	2/7/2006	JDE

**Search Notes (continued)**

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Reexamination

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**SEARCHED**

Class	Subclass	Date	Examiner
370	338	5/31/2006	JDE
	341		
	343		
	431		
	437		
	464		
	480		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR